

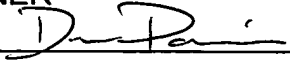
FORM PTO-1449 (SUBSTITUTE) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE INFORMATION DISCLOSURE STATEMENT BY APPLICANT (37 CFR 1.98(b))				Attorney Docket No.: P2001,0325 Appl. No.: Applicant: HOLGER SEDLAK ET AL. Filing Date: November 4, 2003 Group Art Unit:			
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EXAMINER INITIALS	PATENT NO.	DATE	PATENTEE	CLASS	SUB CLASS	FILING DATE
DP	A	5,974,557	10/26/99	Thomas et al.	—	
DP	B	5,465,063	11/7/95	Fukuda et al.	—	
	C					
	D					
	E					
	F					
	G					
	H					
	I					

FOREIGN PATENT DOCUMENT							
		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB CLASS	TRANSL. YES NO
DP	J	43 14 321 A1	2/10/94	Germany	—		
DP	K	41 14 363 C2	12/12/91	Germany	—		
DP	L	691 18 798 T2	4/1/92	Germany	—		
DP	M	0 477 907 B1	4/1/92	Europe	—		
DP	N	1 061 649 A1	12/20/00	Europe	—		

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)		

EXAMINER 	DATE CONSIDERED 3-23-06
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FORM PTO-1449 (SUBSTITUTE) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE INFORMATION DISCLOSURE STATEMENT BY APPLICANT (37 CFR 1.98(b))				Attorney Docket No.: P2001,0325 Appl. No.: Applicant: HOLGER SEDLAK ET AL. Filing Date: November 4, 2003 Group Art Unit:			
EXAMINER INITIALS		PATENT NO.	DATE	PATENTEE	CLASS	SUB CLASS	FILING DATE
	A						
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FOREIGN PATENT DOCUMENT							
		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB CLASS	TRANSL. YES NO
DP	J	10240373	9/11/98	Japan	—		
	K						
	L						
	M						
	N						
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)							
DP		Moore, B. D.: "Tradeoffs in Selecting IC Temperature Sensors", Microprocessors and Microsystems, Elsevier Science B. V., Vol. 23, June 3, 1999, 181-184					
EXAMINER 				DATE CONSIDERED 3-23-06			

FORM PTO-1449 (SUBSTITUTE) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE INFORMATION DISCLOSURE STATEMENT BY APPLICANT (37 CFR 1.98(b))				Attorney Docket No.: P2001,0325 Applic. No. 10/701,058 Applicant: Holger Sedlak et al. Filing Date: November 4, 2003 Group Art Unit: 2836			
U.S. PATENT DOCUMENTS							
EXAMINER INITIALS		PATENT NO.	DATE	PATENTEE	CLASS	SUB CLASS	FILING DATE
	A						
	B						
	C						
	D						
	E						
	F						
	G						
	H						
	I						
FOREIGN PATENT DOCUMENT							
		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB CLASS	TRANSL. YES NO
DP	J	1115033 A	09/23/84	Russia			
DP	K	97119657 A	03/10/98	Russia			
DP	L	00/43860	07/27/00	WIPO			
	M						
	N						
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)							
	O						
	P						
EXAMINER <i>DP</i>				DATE CONSIDERED <i>3-23-06</i>			
EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							